
**Microbeam analysis — Methods of
specimen preparation for analysis of
general powders using WDS and EDS**

*Analyse par microfaisceaux — Méthodes de préparation des
échantillons pour l'analyse des particules*



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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Abbreviated terms	1
5 Analytical purposes and methods of specimen preparation for particle analysis^[1]	1
5.1 Methods of specimen preparation for particle analysis.....	1
5.2 Description of preparation methods.....	2
5.2.1 Analysis of whole particles or surface of particles.....	2
5.2.2 Analysis of cross-section of particles.....	4
5.3 Choosing preparation methods.....	5
6 Electric conductivity processing	6
Annex A (informative) Examples of X-ray strength dependency on tablet-forming pressure	7
Annex B (informative) Example of X-ray strength dependency on tablet-forming particle size	8
Bibliography	9